

Notice of References Cited	Application/Control No. 10/039,333	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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K	US-			
L	US-			
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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